



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS: THOMAS CHUDOBA ET AL

Ser. No.: 10/532,630 Group 2855

FILED : September 7, 2005

TITLE : TEST TABLE FOR MEASURING LATERAL FORCES AND DISPLACEMENTS

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

MAIL STOP Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

S I R :

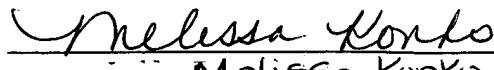
Further to the IDS filed on April 25, 2005, applicants are is submitting a copy of Form PTO-1449 and the two WO references. These references have been discussed in the specification on pages 1 and 2.

Respectfully submitted,
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I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: MAIL STOP Amendment, COMMISSIONER FOR PATENTS, P.O. Box 1450, Alexandria, VA 22313-1450, on April 19, 2006.


Melissa Konko

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. <i>CHUDOBA, T. ET AL PCT</i>	SERIAL NO.: <i>10/532,630</i>		
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: <i>Thomas Chudoba et al</i>	FILING DATE: <i>Sept. 7, 2005</i> GROUP: <i>2855</i>		
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5,051,594	09/1991	Fumihiko et al			
	AB	4,157,818	06/1979	Key			
	AC	3,201,980	08/1965	Webb			
	AD	5,343,748	09/1994	Keasey, et al.			
	AE	2,573,286	10/1951	Baker, et al.			
	AF						
	AG						
	AH						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
	AL	WO 02 16907	02/2002	PCT	<i>ENCLOSED</i>		YES
	AM	WO 99 46576	09/1999	PCT	<i>ENCLOSED</i>		NO
	AN						
	AO						
	AP						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AQ		"Microscratch and Load Relaxation Tests for Ultra-Thin Films" - Wu T. W. Journal of Materials Research, New York, NY, U.S., Vol. 6, no. 2, pages 407-426 February 1991 <i>(To follow)</i>				
	AR		International Search Report				
	AS						
EXAMINER				DATE CONSIDERED			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							